

1. Scope

This specification is applied to Multilayer Ceramic Chip Capacitor (MLCC) for use in electric equipment for the voltage is ranging from 1KV (Include) to 8KV.

The MLCC support for Lead-Free wave and reflow soldering, and electrical characteristic and reliability are same as before. (This product is compliant with the RoHS.)

2. Parts Number Code

С	1206	X	102	K	202	Т
(1)	(2)	(3)	(4)	(5)	(6)	(7)

(1)Product

Product Code	
С	Multilayer Ceramic Chip Capacitor

(2)Chip Size

Code	Length×Width	unit : mm(inch)
0201	0.60× 0.30	(.024× .011)
0402	1.00× 0.50	(.039× .020)
0603	1.60× 0.80	(.063× .031)
0805	2.00× 1.25	(.079× .049)
1206	3.20× 1.60	(.126× .063)
1210	3.20× 2.50	(.126× .098)
1808	4.60× 2.00	(.181× .079)
1812	4.60× 3.20	(.181× .125)
1825	4.60× 6.35	(.181× .250)
2208	5.70× 2.00	(.220× .197)
2211	5.70× 2.80	(.220× .110)
2220	5.70× 5.00	(.220× .197)
2225	5.70× 6.35	(.220× .250)

(3)Temperature Characteristics

	Code	Temperature	Temperature	Temperature
		Characteristic	Range	Coefficient
	N	NPO	-55°C ~+125°C	30 ppm/°C
	L	SL	-25°C ~+85°C	+350~-1000ppm
	Χ	X7R	-55°℃~+125°℃	± 15%
	В	X5R	-55°℃~+85°℃	± 15%
	S	X6S	-55°C ~+105°C	± 22%
	Y	Y5V	-30°C ~+85°C	+22/-82%
	Z	Z5U	+10°C ~+85°C	+22/-56%
	Е	Y5U	-30℃~+85℃	+22/-56%
-				

(4)Capacitance unit :pico farads(pF)

· / I	1 1 /
Code	Nominal Capacitance (pF)
5R0	5.0
120	12.0
151	150.0
102	1,000.0
103	10,000.0
474	470,000.0
105	1,000,000.0
106	10,000,000.0

^{※.} If there is a decimal point, it shall be expressed by an

(5) Capacitance Tolerance

Code	Tolerance	Nominal Capacitance
В	± 0.10 pF	Less Than 10 pF
С	± 0.25 pF	(Include 10 pF)
D	± 0.50 pF	
Е	± 1.00 pF	
F	± 1.00 %	More Than 10 pF
G	± 2.00 %	
J	± 5.00 %	_
K	± 10.0 %	_
M	± 20.0 %	_
Z	+80/-20 %	

(6)Rated Voltage

Code	Rated Voltage (Vdc)
102	1,000
152	1,500
202	2,000
252	2,500
302	3,000
502	5,000
802	8,000

(7)Tapping

Code	Туре
Т	Tape & Reel
В	Bulk

English capital letter R

Page: 1/15



3. Nominal Capacitance and Tolerance

3.1 Standard Combination of Nominal Capacitance and Tolerance

Class	Characteristic	Tolerance		Nominal Capacitance
I	NPO / SL	Less Then 10 pF B (± 0.10 pF)		0.5,1,1.5,2,2.5,3
			C (± 0.25 pF)	0.5,1,1.5,2,2.5,3,3.5,4,4.5,5
			D (± 0.50 pF)	5,6,7,8,9,10
			E (± 1.00 pF)	6,7,8,9,10
		More Than 10 pF	F (±1.00 %)	E-12, E-24 series
			G (±2.00 %)	
			J (± 5.00 %)	
			K (± 10.0 %)	
П	X7R/X5R/X7E	K (± 10.0 %),	M (± 20.0 %)	E-3, E-6 series
	Y5V	M (± 20.0 %), Z	Z(+80/-20 %)	E- 3 series
	Z5U			
	Y5U			

3.2 E series(standard Number)

Standard No.		Application Capacitance										
E- 3	1.0			E- 3 1.0 2.2			4	.7				
E- 6	1	.0	1.	.5	2	.2	3	.3	4.	.7	6	.8
E-12	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
E-24	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
	1.1	1.3	1.6	2.0	2.4	3.0	3.6	4.3	5.1	6.2	7.5	9.1

4. Operation Temperature Range

Class	Characteristic	Temperature Range	Reference Temp.
I	NPO	-55°C ~ +125°C	25℃
	SL	-55°C ~ +125°C	25℃
П	X7R	-55°C ~ +125°C	25 ℃
	X5R	-55°C ~ +85°C	25 ℃
	X6S	-55°C ~ +105°C	25 ℃
	Y5V	-30℃ ~ +85℃	25 ℃
	Z5U	+10°C ~ +85°C	25 ℃
	Y5U	-30°C ~ +85°C	25 ℃
	Other	-25°C ~ +85°C	25 ℃

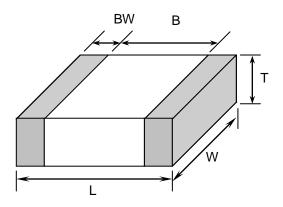
5. Storage Condition

Storage Temperature : 5 to 40° C Relative Humidity : 20 to 70 % Storage Time : 12 months max.



6. Dimensions

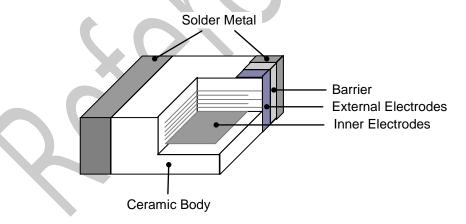
6.1 Configuration and Dimension:



Unit:mm

TYPE	L	W	T (max)	B (min)	BW (min)
0201	0.60 ± 0.03	0.30 ± 0.03	0.33	0.20	0.10
0402	1.00± 0.05	0.50± 0.05	0.55	0.30	0.15
0603	1.60± 0.10	0.80± 0.10	1.00	0.40	0.15
0805	2.00± 0.20	1.25± 0.20	1.45	0.70	0.20
1206	3.20 ± 0.30	1.60± 0.20	1.80	1.50	0.30
1210	3.20 ± 0.30	2.50± 0.20	2.60	1.60	0.30
1808	4.60± 0.30	2.00± 0.20	2.20	2.50	0.30
1812	4.60± 0.30	3.20 ± 0.30	3.00	2.50	0.30
1825	4.60± 0.30	6.35± 0.40	2.60	2.50	0.30
2208	5.70± 0.40	2.00± 0.20	2.20	3.50	0.30
2211	5.70± 0.40	2.80± 0.40	3.00	3.50	0.30
2220	5.70± 0.40	5.00± 0.40	3.00	3.50	0.30
2225	5.70± 0.40	6.35± 0.40	3.00	3.50	0.30

6.2 Termination Type:





7. Performance

No.	Item		Specific	ation	Test Condition	
1	Visua	ıl	No abnormal exterio	or appearance	Visual inspection	
2	Dimens	ion	See Page 3		Visual inspection	
3	Insulati Resistai		10,000MΩ or 500/C Product Whichever		V≦500V, Rated Voltage V>500V, Applied 500Vdc Charge Time:60sec. Is applied less than 50mA current.	
4	Capacitance	Class I NPO/SL	Within The Specified	Tolerance	Class I : NPO/SL	
		Class II	Within The Specified	Tolerance	Capacitance Frequency Voltage C≤1000pF 1MHz±10% 1.0±0.2Vrms C>1000pF 1KHz±10%	
5	Q Tanō	Class I NPO/SL Class II	More Than 30pF: Q 30pF & Below: Q≥4 (C: Capacitance, p Char. X7R Z5U/Y5U	00 + 20C	Class II : Frequency Voltage X7R 1KHz±10% 1.0±0.2Vrms Z5U/Y5U 1KHz±10% 1.0±0.2Vrms Perform a heat temperature at 150±5℃ for 30min. then place room temp. for 24±2hr.	
6	Withstan Voltag		No dielectric breakdown or mechanical breakdown		200% /150%/120%/100% Rated Voltage For information which product has which applied voltage, please contact with HEC sales representative. Voltage ramp up rate ≤ 500v/sec for 1~5 sec. charge/discharge Current is less than 50mA. ※ Withstanding voltage testing requires immersion of the element in a isolation fluid prevent arcing on the chip surface, at voltage over 1000Vdc.	
7	Temperature Capacitance Coefficient	Class I	Char. Temp. Range NPO -55°C ~+125°C SL -30°C ~+85°C Char. Temp. Range X7R -55°C ~+125°C Y5U -30°C ~+85°C Z5U +10°C ~+85°C	+350~-1000ppm Cap. Change(%) ± 15%	[C2-C1/C1(T2-T1)] × 100% Class	
8	Adhesive Strength of Termination No indication of peeling shall occur on the terminal electrode.		Pull force shall be applied for 10± 1 second. ≤ 06035N(= 0.5 Kg·f) > 060310N(= 1.0 Kg·f) N·f			
9		Appear- ance C-Meter	Capacitance Change Char. Cap NPO ≤ ± SL ≤ ± X7R ≤ ±		Bending shall be applied to the 1.0 mm with 1.0 mm/sec. R230 Bending Limit C Meter 45±1mm 45±1mm	



No.	. Item		Speci	fication	Test Condition		
10	Solde	rability	More than 90% of the terminal surface is to be soldered newly, so metal part does not come out or dissolve.		Solder Temperature: 245±5°C Dip Time: 5 ± 0.5 sec. Immersing Speed: 25±10% mm/s Solder: Lead Free Solder Flux: Rosin Preheat: At 80~120°C for 10~30sec.		
11	Resistance		No mechanical dar	nage shall occur.	Class		
	To Soldering Heat	ance Capacit- ance	Characteristic Class I (NPO/SL)	Cap. Change Within ± 2.5% or ±0.25pFwhichever is larger of initial value	room temperature after one hour heat treatment at 150 +0/-10°C before initial measure. Preheat : At 150± 10°C For 60~120sec. Dip : Solder Temperature of 260± 5°C Dip Time : 10 ± 1sec. Immersing Speed : 25±10% mm/s		
			Class X7R II Z5U/Y5U	Within ± 10% Within ± 20%	Flux :Rosin		
		Q Class I Tan δ	To satisfy the speci		Measure at room temperature after cooling for Class I : 24 ± 2 Hours Class II : 48 ± 4 Hours		
		Class II Insulation Resistance Withstand	To satisfy the speci				
		Voltage					
12	Tempera ture	Appear- ance	No mechanical dar		Class II capacitor shall be set for 48± 4 hours at room temperature after one hour heat treatment at 150 +0/-10 °C before initial measure.		
	Cycle	Capacit- ance	Class I (NPO/SL) Class X7R II Z5U/Y5U	Cap. Change Within ± 2.5% or ±0.25pFwhichever is larger of initial value Within ± 7.5% Within ± 20%	Capacitor shall be subjected to five cycles of the temperature cycle as following: Step Temp.(°C) Time(min) 1 Min Rated Temp. +0/-3 30		
		Q Class I Tan δ	To satisfy the speci	fied initial value	2 25 3 3 Max Rated Temp. +3/-0 30 4 25 3		
		Class II Insulation Resistance	To satisfy the speci		Measure at room temperature after cooling for Class I :24 ± 2 Hrs Class II :48 ± 4 Hrs Solder the capacitor on P.C. board shown in Fig 2. before testing.		
13	Humidity	Appear- ance Capacit- ance	No mechanical dar Characteristic Class I (NPO/SL)	Cap. Change Within ± 5.0% or ±0.5pF whichever is larger of initial value	Class II capacitor shall be set for 48± 4 hours at room temperature after one hour heat treatment at 150+0/-10 °C before initial measure. Temperature: 40± 2°C		
		Q Class I	More Than 30pF : 0 30pF & Below: Q ≧	Within ± 15% Within ± 30% Q ≥ 350 ≥ 275 +2.5×C	Measure at room temperature after cooling for Class I : 24 ± 2Hrs Class II : 48 ± 4Hrs		
			Solder the capacitor on P.C. board shown in Fig 2. before testing.				
		Insulation Resistance	1,000M Ω or 50/C smaller.	Ω whichever is			

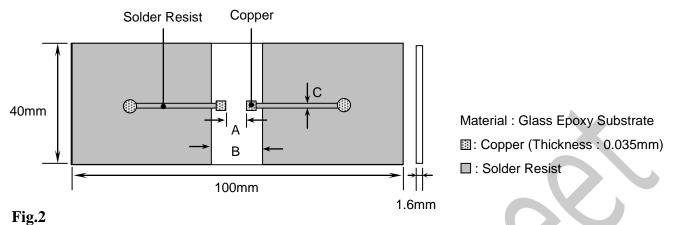
Page : 5/15

Reference sheet

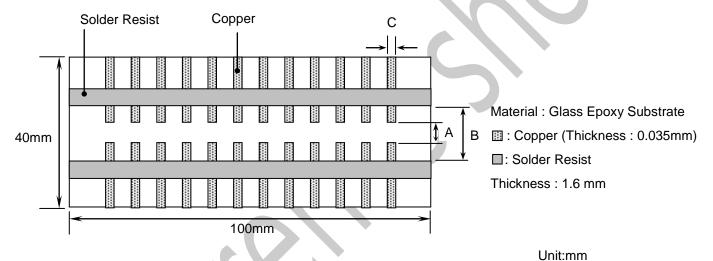
No.	Iter	n		Speci	fication	Test Condition	
14	High Temperature	Appear- ance	No med			Class II capacitors applied DC voltage (following table) is applied for one hour at maximum operation temperature $\pm 3^{\circ}\mathbb{C}$ then shall be set for	
	Load	Capacit-	Characteristic Cap. Change		Cap. Change		
		ance	Class I		Within ±3.0% or	48±4 hours at room temperature and the initial	
			(NPO/S	SL)	± 0.3pFwhichever	measurement shall be conducted.	
			`	,	is larger	Voltage Conditioning :	
			Class	X7R	Within ± 15%]	
			П	Z5U/Y5U	Within ± 30%	For information which product has which applied	
		Q	More Th	han 30pF :	Q ≧ 350	voltage, please contact with HEC sales representative.	
		Class I	30pF &	Below:Q ≧	275 + 2.5 x C		
		Tan δ	Cha		maximum	Current Applied : 50 mA Max.	
		Class II	X7		5.0%	Measure at room temperature after cooling for	
			Z5U/`		5.0%	Class I : 24 ± 2 Hours	
			· ·		Ω whichever is	Class II: 48 ± 4 Hours	
		Resistance	smaller.	•	(C in Farad)		
15	Vibration	Appear-	No med	chanical dar	mage shall occur	Solder the capacitor on P.C. Board shown in	
		ance				Fig 2. before testing.	
		Capacit-		racteristic	Cap. Change		
		ance	Class I		Within ± 2.5% or	Vibrate the capacitor with amplitude of 1.5mm	
			(NPO/S	SL)	± 0.25pFwhichever		
					is larger	55Hz and back to 10Hz in about 1 min.	
			Class	X7R	Within ± 7.5%		
		_	П	Z5U/Y5U	Within ± 20%	Repeat this for 2 hours each in 3perpendicular directions.	
		Q	To satis	ty the spec	ified initial value	uli ections.	
		Class I	T		W . 17 . W . 1 . 1	4	
		Tan δ	io satis	try the spec	ified initial value		
		Class II	To cotic	fu the ence	ified initial value	-	
		Insulation Resistance		iy trie spec	ified initial value		
		resistance					



Fig.1
P.C. Board for Bending Strength Test



Test Substrate



Type	А	В	С
0201	0.2	0.9	0.4
0402	0.5	1.5	0.6
0603	1.0	3.0	1.0
0805	1.2	4.0	1.6
1206	2.2	5.0	2.0
1210	2.2	5.0	2.9
1808	3.5	7.0	2.5
1812	3.5	7.0	3.7
2208	4.5	0.8	2.5
2211	4.5	8.0	3.0
2220	4.5	8.0	5.6

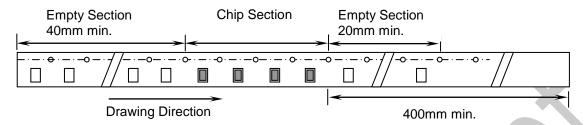


8. Packing

8.1 Bulk Packing

According to customer request.

8.2 Chip Capacitors Tape Packing



8.3 Material And Quantity

Tape	0201	0402	0603/0805		
Material	T≦0.33mm	T≦0.55mm	T≦0.90mm	T>0.90mm	
Paper	15,000 pcs/Reel	10,000 pcs/Reel	4,000 pcs/Reel	NA	
Plastic	NA	NA	NA	3,000 pcs/Reel	

Tape	1206					
Material	T≦0.90mm	0.90mm < T ≦ 1.25mm	T>1.25mm			
Paper	4,000 pcs/Reel	NA	NA			
Plastic	NA	3,000 pcs/Reel	2,000 pcs/Reel			

Tape	1808/1210						
Material	T≦1.25mm	1.25mm < T ≤ 2.40mm	T>2.40mm				
Paper	NA	NA	NA				
Plastic	3000 pcs/Reel	2000 pcs/Reel	500/1,000 pcs/Reel				

Tape	1812/22	11/2220	1825	2208	
Material	T≦2.20mm	T>2.20mm	T≦2.20mm	T>2.20mm	T≦2.20mm
Paper	NA	NA	NA	NA	NA
Plastic	1000 pcs/Reel	700 pcs/Reel	700 pcs/Reel	400 pcs/Reel	1000 pcs/Reel

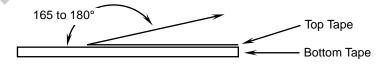
NA: Not Available

8.4 Cover Tape Reel Off Force

8.4.1 Peel-Off Force

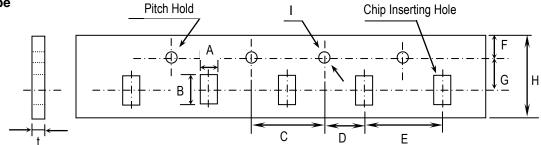
 $5 g \cdot f \leq Peel-Off Force \leq 70 g \cdot f$

8.4.2 Measure Method







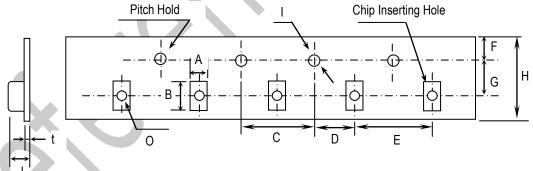


Unit:mm

TYPE	Α	В	С	D	Е
0201	0.37± 0.1	0.67± 0.1	4.00± 0.1	2.00± 0.05	2.00± 0.1
0402	0.61± 0.1	1.20± 0.1			
0603	1.10± 0.2	1.90± 0.2			4.00± 0.1
0805	1.50± 0.2	2.30± 0.2			
1206	1.90± 0.2	3.50± 0.2			
1210	2.90± 0.2	3.60± 0.2			

TYPE	F	G	Н		t
0201	1.75± 0.10	3.50± 0.05	8.0± 0.30	φ 1.50 +0.10/-0	1.10 max.
0402					
0603					
0805					
1206					
1210					

8.6 Plastic Tape



Unit:mm

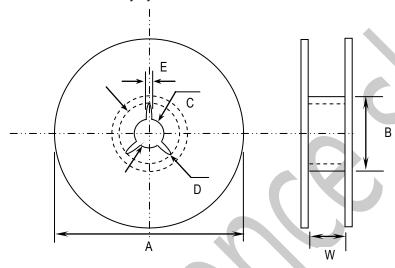
Type	Α	В	С	D	E	F
0805	1.5±0.2	2.3±0.2	4.0± 0.1	2.0± 0.05	4.0± 0.1	1.75± 0.1
1206	1.9±0.2	3.5±0.2				
1210	2.9±0.2	3.6±0.2				
1808	2.5±0.2	4.9±0.2				
1812	3.6±0.2	4.9±0.2			8.0± 0.1	
1825	6.9±0.2	4.9±0.2				
2208	2.5±0.2	6.1±0.2				
2211	3.2±0.2	6.1±0.2				
2220	5.4±0.2	6.1±0.2				
2225	6.9±0.2	6.1±0.2				



Туре	G	Н	I	J	t	0
0805	3.5 ± 0.05	8.0 ± 0.3	φ 1.5+0.1/-0	3.0 max.	0.3 max.	1.0± 0.1
1206						
1210						
1808	5.5± 0.05	12.0 ± 0.3		4.0 max.		1.5± 0.1
1812						
1825						
2208						
2211						
2220						
2225						

8.7 Reel Dimensions

Reel Material : Polystyrene



Unit:mm

Type	А	В	С	D	Е	W
0201	φ 382 max	φ 50 min	φ 13± 0.5	φ 21± 0.8	2.0±0.5	10± 0.15
0402						
0603						
0805						
1206						
1210						
1808	φ 178±0.2	φ 60±0.2				13±0.3
1812						
1825						
2208						
2211						
2220						
2225						



Precautionary Notes:

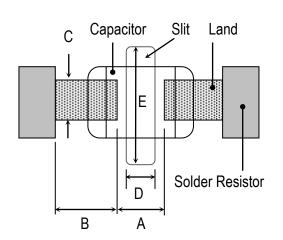
1. Storage

Store the capacitors where the temperature and relative humidity don't exceed 40°C and 70%RH. We recommend that the capacitors be used within 12 months from the date of manufacturing. Store the products in the original package and do not open the outer wrapped, polyethylene bag, till just before usage. If it is open, seal it as soon as possible or keep it in a desiccant with a desiccation agent.

2. Construction of Board Pattern

Improper circuit layout and pad/land size may cause excessive or not enough solder amount on the PC board. Not enough solder may create weak joint, and excessive solder may increase the potential of mechanical or thermal cracks on the ceramic capacitor. Therefore we recommend the land size to be as shown in the following table:

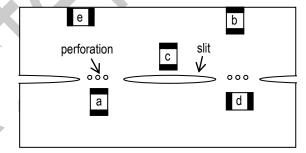
2.1 Size and recommend land dimensions for reflow soldering .



EIA Codo	Chip (mm)		Land (mm)				
EIA Code	L	W	Α	В	С	D	Е
0201	0.60	0.30	0.2~0.3	0.2~0.4	0.2~0.4		-
0402	1.00	0.50	0.3~0.5	0.3~0.5	0.4~0.6		1
0603	1.60	0.80	0.4~0.6	0.6~0.7	0.6~0.8		1
0805	2.00	1.25	0.7~0.9	0.6~0.8	0.8~1.1		
1206	3.20	1.60	2.2~2.4	0.8~0.9	1.0~1.4	1.0~2.0	3.2~3.7
1210	3.20	2.50	2.2~2.4	1.0~1.2	1.8~2.3	1.0~2.0	4.1~4.6
1808	4.60	2.00	2.8~3.4	1.8~2.0	1.5~1.8	1.0~2.8	3.6~4.1
1812	4.60	3.20	2.8~3.4	1.8~2.0	2.3~3.0	1.0~2.8	4.8~5.3
1825	4.60	6.35	2.8~3.4	1.8~2.0	5.1~5.8	1.0~4.0	7.1~8.3
2208	5.70	2.00	4.0~4.6	2.0~2.2	1.5~1.8	1.0~4.0	3.6~4.1
2211	5.70	2.80	4.0~4.6	2.0~2.2	2.0~2.6	1.0~4.0	4.4~4.9
2220	5.70	5.00	4.0~4.6	2.0~2.2	3.5~4.8	1.0~4.0	6.6~7.1
2225	5.70	6.35	4.0~4.6	2.0~2.2	5.1~5.8	1.0~4.0	7.1~8.3

2.2 Mechanical strength varies according to location of chip capacitors on the P.C. board. Design layout of components on the PC board such a way to minimize the stress imposed on the components, upon flexure of the boards in depanelization or other processes.

Component layout close to the edge of the board or the "depanelization line" is not recommended. Susceptibility to stress is in the order of: a>b>c and d>e



Page: 11/15

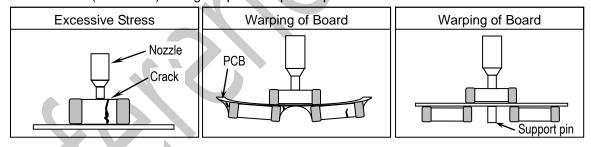


2.3 Layout Recommendation

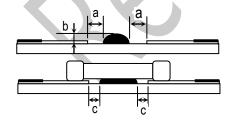
Example	Use of Common Solder Land	Solder With Chassis	Use of Common Solder Land With Other SMD
Need to Avoid	Chip Solder Adhesive PCB Solder Land	Chassis Excessive Solder	Solder Land
Recommendation	Chip Solder Resist Adhesive Solder Land	Solder Resist β $\alpha > \beta$	

3. Mounting

3.1 Sometimes crack is caused by the impact load due to suction nozzle in pick and place operation. In pick and place operation, if the low dead point is too low, excessive stress is applied to component. This may cause cracks in the ceramic capacitor, therefore it is required to move low dead point of a suction nozzle to the higher level to minimize the board warp age and stress on the components. Nozzle pressure is typically adjusted to 1N to 3N (static load) during the pick and place operation.



3.2 Amount of Adhesive



Example: 0805 & 1206

а	0.2mm min.
b	70 ~ 100 μm
С	Do not touch the solder land

Page: 12/15

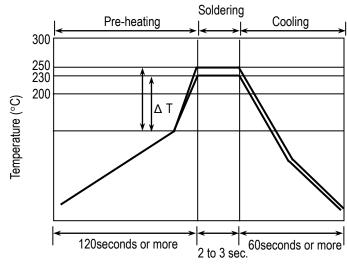


4. Soldering

4.1. Wave Soldering

Most of components are wave soldered with solder at 230 to 250°C. Adequate care must be taken to prevent the potential of thermal cracks on the ceramic capacitors. Refer to the soldering methods below for optimum soldering benefits.

Recommend flow soldering temperature Profile



Soldering Method	Change in Temp.(°C)
1206 and Under	Δ T ≤ 100~130 max.

To optimize the result of soldering, proper preheating is essential:

- 1) Preheat temperature is too low
 - a. Flux flows to easily
 - b. Possibility of thermal cracks
- 2) Preheat temperature is too high
 - a. Flux deteriorates even when oxide film is removed
 - b. Causes warping of circuit board
 - c. Loss of reliability in chip and other components

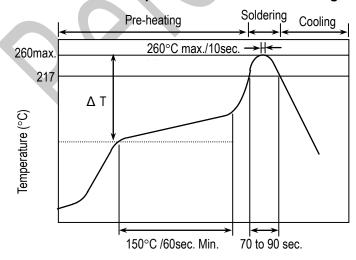
Cooling Condition:

Natural cooling using air is recommended. If the chips are dipped into a solvent for cleaning, the temperature difference (Δ T) between the solvent and the chips must be less than 100°C.

4.2 Reflow Soldering

Preheat and gradual increase in temperature to the reflow temperature is recommended to decrease the potential of thermal crack on the components. The recommended heating rate depends on the size of component, however it should not exceed 3°C/Sec.

Recommend reflow profile for Lead-Free soldering temperature Profile (MIL-STD-202G #210F)



The cycles of soldering : Twice (max.)

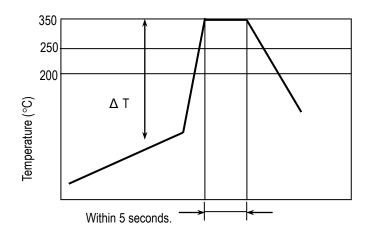
Soldering Method	Change in Temp.(°C)
1206 and Under	Δ T ≦ 190 °C
1210 and Over	Δ T ≦ 130 °C

Page: 13/15



4.3 Hand Soldering

Sudden temperature change in components, results in a temperature gradient recommended in the following table, and therefore may cause internal thermal cracks in the components. In general a hand soldering method is not recommended unless proper preheating and handling practices have been taken. Care must also be taken not to touch the ceramic body of the capacitor with the tip of solder Iron.



Soldering Method	Change in Temp.(°C)
1206 and Under	Δ T \leq 150 $^{\circ}$ C
1210 and Over	Δ T \leq 130 $^{\circ}$ C

How to Solder Repair by Solder Iron

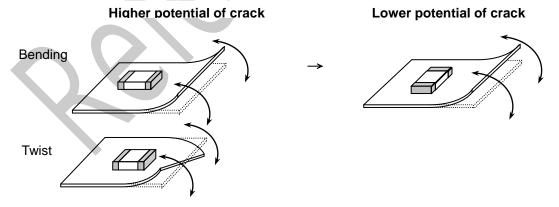
1) Selection of the soldering iron tip

The required temperature of solder iron for any type of repair depends on the type of the tip, the substrate material, and the solder land size.

- 2) recommended solder iron condition
 - a.) Preheating Condition: Board and components should be preheated sufficiently at 150°C or over, and soldering should be conducted with soldering iron as boards and components are maintained at sufficient temperatures.
 - b.) Soldering iron power shall not exceed 30 W.
 - c.) Soldering iron tip diameter shall not exceed 3mm.
 - d.) Temperature of iron tip shall not exceed 350°C., and the process should be finished within 5 seconds. (refer to MIL-STD-202G)
 - f.) Do not touch the ceramic body with the tip of solder iron. Direct contact of the soldering iron tip to ceramic body may cause thermal cracks.
 - g.) After soldering operation, let the products cool down gradually in the room temperature.

5. Handling after chip mounted

5.1 Proper handling is recommended, since excessive bending and twist of the board, depends on the orientation of the chip on the board, may induce mechanical stress and cause internal crack in the capacitor.



5.2 There is a potential of crack if board is warped due to excessive load by check pin



Page: 14/15



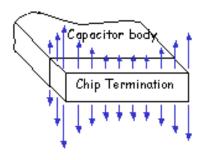
5.3 Mechanical stress due to warping and torsion.

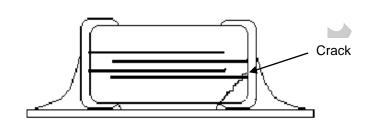
X:Tensile Stress

- (a) Crack occurrence ratio will be increased by manual separation.
- (b) Crack occurrence ratio will be increased by tensile force, rather than compressive force.



Capacitor Stress Analysis





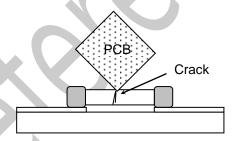
:Compressive Stress

6. Handling of Loose Chip Capacitor

6.1 If dropped the chip capacitor may crack.



6.2 In piling and stacking of the P.C. boards after mounting for storage or handling, the corner of the P.C. board may hit the chip capacitor mounted on another board to cause crack.



7. Safekeeping condition and period

For safekeeping of the products, we recommend to keep the storage temperature between +5 to +40°C and under humidity of 20 to 70% RH. The shelf life of capacitors is 12 months.

Page: 15/15